Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/624,354	HOSAKA, YOSHIF	IIRO
Examiner	Art Unit	

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Class	Subclass	Date	Examiner					
705	28	8/28/2007	V.F					
705	27	8/28/2007	V.F					
235	375	8/28/2007	V.F					

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